TOSHIBA Field Effect Transistor Silicon N Channel Junction Type

# 2SK3376MFV

#### For ECM

Application for Ultra-compact ECM

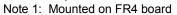
### Absolute Maximum Ratings (Ta=25°C)

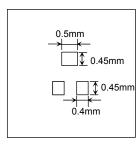
Characteristic	Symbol	Rating	Unit
Gate-Drain voltage	V <sub>GDO</sub>	-20	V
Gate Current	l <sub>G</sub>	10	mA
Drain power dissipation (Ta = 25°C)	P <sub>D</sub> (Note 1)	150	mW
Junction Temperature	Тj	125	°C
Storage temperature range	T <sub>stg</sub>	-55~125	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling

Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

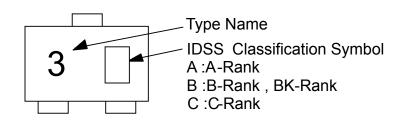




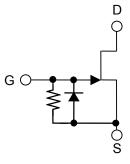
#### **IDSS CLASSIFICATION**

A-Rank	80 to 200µA
B-Rank	170 to 300µA
C-Rank	270 to 480µA
BK-Rank	150 to 350µA

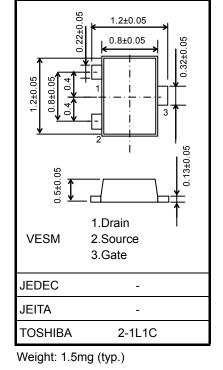
#### Marking



#### **Equivalent Circuit**



Unit: mm



## Electrical Characteristics (A-Rank IDSS Ta=25°C)

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain Current	I <sub>DSS</sub>	$V_{DS}=2~V,~V_{GS}=0$	80		200	μA
Drain Current	I <sub>D</sub>	$V_{DD} = 2 \text{ V}, \text{ RL= } 2k\Omega, \text{Cg} = 3pF$			240	μA
Gate-Source Cut-off Voltage	V <sub>GS(OFF)</sub>	$V_{DS} = 2 \text{ V}, \text{ I}_{D} = 1 \mu \text{A}$	-0.1	_	-0.8	V
Forward transfer admittance	Y <sub>fs</sub>	$V_{DS} = 2 V, V_{GS} = 0V$	0.7	1.4	_	mS
Input capacitance	C <sub>iss</sub>	$V_{DS} = 2 V, V_{GS} = 0, f = 1 MHz$	_	5.5	_	pF
Voltage Gain	Gv	$V_{DD} = 2V$ , RL= $2k\Omega$ , Cg = $3pF$ , f = $1kHz$	-13.5	_	-9.0	dB
Delta Voltage Gain	DGv(f)	$V_{DD} = 2V$ , RL= $2k\Omega$ , Cg = $3pF$ , f = 1kHz to 100Hz	_	_	-2.0	dB
Delta Voltage Gain	DGv(V)	$V_{DD} = 2V$ to 1V, RL= $2k\Omega$ , Cg = $3pF$ , f = $1kHz$	_	_	-4.0	dB
Noise Voltage	VN	$V_{DD}$ = 2V, RL= 1k $\Omega$ ,Cg = 3pF,Gv=80dB,f=A-Curve Filter		—	47	mV

### **Electrical Characteristics (B-Rank IDSS Ta=25°C)**

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain Current	I <sub>DSS</sub>	$V_{DS}=2~V,~V_{GS}=0$	170	_	300	μA
Drain Current	I <sub>D</sub>	$V_{DD} = 2 \text{ V}, \text{ RL} = 2 \text{k}\Omega, \text{Cg} = 3 \text{pF}$	_	_	340	μA
Gate-Source Cut-off Voltage	V <sub>GS(OFF)</sub>	$V_{DS} = 2 V, I_D = 1 \mu A$	-0.15	_	-1.0	V
Forward transfer admittance	Y <sub>fs</sub>	$V_{DS} = 2 V, V_{GS} = 0V$	0.7	1.4	_	mS
Input capacitance	C <sub>iss</sub>	$V_{DS} = 2 V, V_{GS} = 0, f = 1 MHz$	_	5.5	_	pF
Voltage Gain	Gv	$V_{DD} = 2V$ , RL= $2k\Omega$ , Cg = $3pF$ , f = $1kHz$	-11.5	_	-8.0	dB
Delta Voltage Gain	DGv(f)	$V_{DD} = 2V$ , RL= $2k\Omega$ , Cg = $3pF$ , f = 1kHz to 100Hz	_	_	-2.0	dB
Delta Voltage Gain	DGv(V)	$V_{DD} = 2V$ to 1V, RL= $2k\Omega$ , Cg = $3pF$ , f = $1kHz$	_	_	-7.0	dB
Noise Voltage	VN	$V_{DD}$ = 2V, RL= 1k $\Omega$ ,Cg = 3pF,Gv=80dB,f=A-Curve Filter		—	50	mV

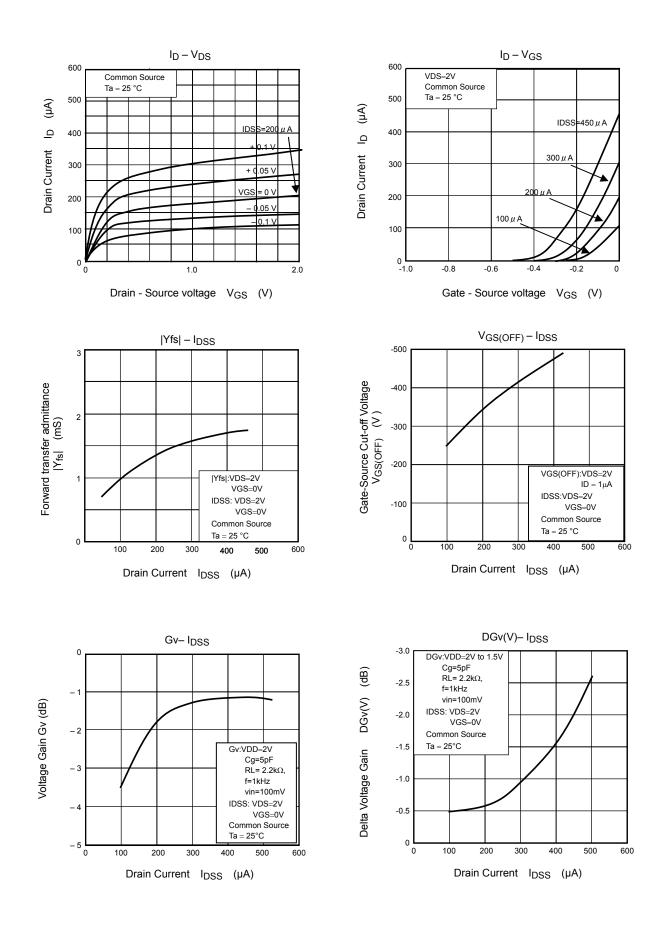
## Electrical Characteristics (C-Rank IDSS Ta=25°C)

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain Current	I <sub>DSS</sub>	$V_{DS}=2~V,~V_{GS}=0$	270	_	480	μA
Drain Current	I <sub>D</sub>	$V_{DD} = 2 V, RL= 2k\Omega, Cg = 3pF$	_	_	520	μA
Gate-Source Cut-off Voltage	V <sub>GS(OFF)</sub>	$V_{DS}=2~V,~I_{D}=1\mu A$	-0.2	_	-1.2	V
Forward transfer admittance	Y <sub>fs</sub>	$V_{DS} = 2 V, V_{GS} = 0V$	0.7	1.4	_	mS
Input capacitance	C <sub>iss</sub>	$V_{DS} = 2 V, V_{GS} = 0, f = 1 MHz$	_	5.5	_	pF
Voltage Gain	Gv	$V_{DD} = 2V$ , RL= $2k\Omega$ , Cg = $3pF$ , f = $1kHz$	-10.5	_	-6.75	dB
Delta Voltage Gain	DGv(f)	$V_{DD} = 2V$ , RL= 2k $\Omega$ ,Cg = 3pF,f = 1kHz to 100Hz	_	_	-2.0	dB
Delta Voltage Gain	DGv(V)	$V_{DD} = 2V$ to 1V, RL= $2k\Omega$ , Cg = $3pF$ , f = $1kHz$	_	_	-20	dB
Noise Voltage	VN	$V_{DD}$ = 2V, RL= 1k $\Omega$ ,Cg = 3pF,Gv=80dB,f=A-Curve Filter			75	mV

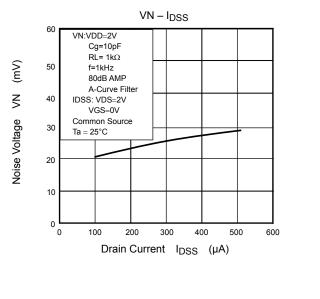
# Electrical Characteristics (BK-Rank IDSS Ta=25°C)

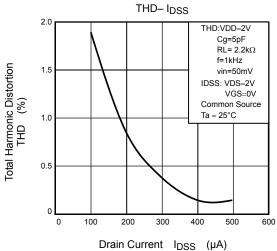
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain Current	I <sub>DSS</sub>	$V_{DS}=2~V,~V_{GS}=0$	150	_	350	μA
Drain Current	I <sub>D</sub>	$V_{DD} = 2 \text{ V}, \text{ RL} = 2k\Omega, \text{Cg} = 3pF$	_	_	390	μA
Gate-Source Cut-off Voltage	V <sub>GS(OFF)</sub>	$V_{DS} = 2 V, I_D = 1 \mu A$	-0.125	_	-1.1	V
Forward transfer admittance	Y <sub>fs</sub>	$V_{DS} = 2 V, V_{GS} = 0V$	0.7	1.4	_	mS
Input capacitance	C <sub>iss</sub>	$V_{DS} = 2 V, V_{GS} = 0, f = 1 MHz$	_	5.5	_	pF
Voltage Gain	Gv	$V_{DD} = 2V$ , RL= $2k\Omega$ , Cg = $3pF$ , f = $1kHz$	-12.0	_	-7.50	dB
Delta Voltage Gain	DGv(f)	$V_{DD} = 2V$ , RL= $2k\Omega$ , Cg = $3pF$ , f = 1kHz to 100Hz	_	_	-2.0	dB
Delta Voltage Gain	DGv(V)	$V_{DD} = 2V$ to 1V, RL= $2k\Omega$ , Cg = $3pF$ , f = $1kHz$	_	_	-13.5	dB
Noise Voltage	VN	$V_{DD}$ = 2V, RL= 1k $\Omega$ ,Cg = 3pF,Gv=80dB,f=A-Curve Filter			65	mV

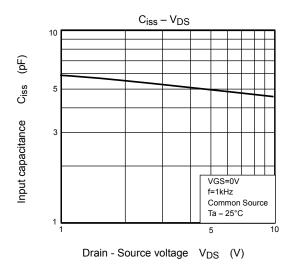
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